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Form PTO-1449 (Substitute)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Attorney Docket Number <b>LAZE-01011US1</b>		Serial/Patent Number <b>10/684,883</b>	
<b>Information Disclosure Statement</b> <b>BY APPLICANT</b> (Use several sheets if necessary)				Applicant/Patent Owner <b>Thomas F. Rust</b>			
				Filing/Issue Date <b>10/14/2003</b>		Group Art Unit <b>2655</b>	
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	8	4,987,312	01/22/91	Eigler	250	492.3	11/07/89
	9	5,038,322	08/06/91	Van Loenen	365	114	02/03/89
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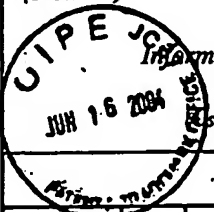
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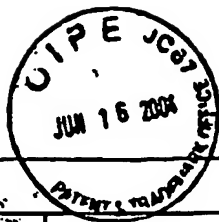


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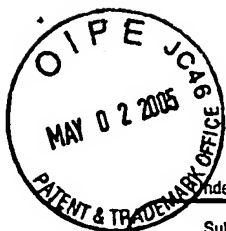
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Examiner Initial		Application Number	Filing Date	First Named Inventor	Petition to Expunge? Yes   No		

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Examiner	C. Phung			Date Considered	1/14/05			
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STATEMENT BY APPLICANT**

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Sheet 1 of 1

**Complete if Known**

Application Number	10/684,883
Filing Date	10/14/2003
First Named Inventor	Thomas F. Rust
Art Unit	2824
Examiner Name	Phung, Anh K.
Attorney Docket Number	LAZE-01011US1

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		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)				
ap		WO 00/36608	06/22/00	Thomas F. Rust		

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Signature

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